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#### Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

Product Status	Active
Core Processor	Coldfire V2
Core Size	32-Bit Single-Core
Speed	60MHz
Connectivity	Ethernet, I <sup>2</sup> C, SPI, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	73
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 3.6V
Data Converters	A/D 8x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	112-LQFP
Supplier Device Package	112-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mcf52233cal60

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong





Module	52230	52231	52232	52233	52234	52235	52236
Version 2 ColdFire Core with EMAC (Enhanced Multiply-Accumulate Unit)	•	•	•	•	•	•	•
System Clock (MHz)	60	60	50	60	60	60	50
Performance (Dhrystone 2.1 MIPS)	56	56	46	56	56	56	46
Flash / Static RAM (SRAM)	128/32 Kbytes	128/32 Kbytes	128/32 Kbytes	256/32 Kbytes	256/32 Kbytes	256/32 Kbytes	256/32 Kbytes
Interrupt Controllers (INTC0/INTC1)	•	•	•	•	•	•	٠
Fast Analog-to-Digital Converter (ADC)	•	•	•	•	•	•	٠
Random Number Generator and Crypto Acceleration Unit (CAU)	—	—	—	—	—	•	_
FlexCAN 2.0B Module	—	•	—	—	•	•	
Fast Ethernet Controller (FEC) with on-chip interface (EPHY)	•	•	•	•	•	•	•
Four-channel Direct-Memory Access (DMA)	•	•	•	•	•	•	•
Software Watchdog Timer (WDT)	•	•	•	•	•	•	•
Programmable Interrupt Timer	2	2	2	2	2	2	2
Four-Channel General Purpose Timer	•	•	•	•	•	•	•
32-bit DMA Timers	4	4	4	4	4	4	4
QSPI	•	•	•	•	•	•	٠
UART(s)	3	3	3	3	3	3	3
l <sup>2</sup> C	•	•	•	•	•	•	٠
Eight/Four-channel 8/16-bit PWM Timer	•	•	•	•	•	•	٠
General Purpose I/O Module (GPIO)	•	•	•	•	•	•	•
Chip Configuration and Reset Controller Module	•	•	•	•	•	•	•
Background Debug Mode (BDM)	•	•	•	•	•	•	•
JTAG - IEEE 1149.1 Test Access Port <sup>1</sup>	•	•	•	•	•	•	•
Package	80 LQFP 112 LQFP	80 LQFP 112 LQFP	80 LQFP	80 LQFP 112 LQFP	112 LQFP 121 MAPBGA	112 LQFP 121 MAPBGA	80 LQFP

#### Table 1. MCF52235 Family Configurations

<sup>1</sup> The full debug/trace interface is available only on the 112- and 121-pin packages. A reduced debug interface is bonded on the 80-pin package.



### 1.1 Block Diagram

The MCF52235 (or its variants) comes in 80- and 112-pin low-profile quad flat pack packages (LQFP) and a 121 MAPBGA, and operates in single-chip mode only. Figure 1 shows a top-level block diagram of the MCF52235.





### 1.2 Features

This document contains information on a new product under development. Freescale reserves the right to change or discontinue this product without notice. Specifications and information herein are subject to change without notice.

- Unique vector number for each interrupt source
- Ability to mask any individual interrupt source or all interrupt sources (global mask-all)
- Support for hardware and software interrupt acknowledge (IACK) cycles
- Combinatorial path to provide wake-up from low power modes
- DMA controller
  - Four fully programmable channels
  - Dual-address transfer support with 8-, 16-, and 32-bit data capability, along with support for 16-byte (4 x 32-bit) burst transfers
  - Source/destination address pointers that can increment or remain constant
  - 24-bit byte transfer counter per channel
  - Auto-alignment transfers supported for efficient block movement
  - Bursting and cycle steal support
  - Software-programmable DMA requesters for the UARTs (3) and 32-bit timers (4)
- Reset
  - Separate reset in and reset out signals
  - Seven sources of reset:
    - Power-on reset (POR)
    - External
    - Software
    - Watchdog
    - Loss of clock
    - Loss of lock
    - Low-voltage detection (LVD)
  - Status flag indication of source of last reset
- Chip integration module (CIM)
  - System configuration during reset
  - Selects one of three clock modes
  - Configures output pad drive strength
  - Unique part identification number and part revision number
- General purpose I/O interface
  - Up to 56 bits of general purpose I/O
  - Bit manipulation supported via set/clear functions
  - Programmable drive strengths
  - Unused peripheral pins may be used as extra GPIO
- JTAG support for system level board testing

### 1.2.2 V2 Core Overview

The version 2 ColdFire processor core is comprised of two separate pipelines decoupled by an instruction buffer. The two-stage instruction fetch pipeline (IFP) is responsible for instruction-address generation and instruction fetch. The instruction buffer is a first-in-first-out (FIFO) buffer that holds prefetched instructions awaiting execution in the operand execution pipeline (OEP). The OEP includes two pipeline stages. The first stage decodes instructions and selects operands (DSOC); the second stage (AGEX) performs instruction execution and calculates operand effective addresses, if needed.

The V2 core implements the ColdFire instruction set architecture revision A+ with added support for a separate user stack pointer register and four new instructions to assist in bit processing. Additionally, the MCF52235 core includes the enhanced multiply-accumulate (EMAC) unit for improved signal processing capabilities. The EMAC implements a three-stage arithmetic



### **1.2.15** Periodic Interrupt Timers (PIT0 and PIT1)

The two periodic interrupt timers (PIT0 and PIT1) are 16-bit timers that provide interrupts at regular intervals with minimal processor intervention. Each timer can count down from the value written in its PIT modulus register or can be a free-running down-counter.

### 1.2.16 Pulse Width Modulation (PWM) Timers

The MCF52235 has an 8-channel, 8-bit PWM timer. Each channel has a programmable period and duty cycle as well as a dedicated counter. Each of the modulators can create independent continuous waveforms with software-selectable duty rates from 0 to 100%. The PWM outputs have programmable polarity and can be programmed as left-aligned outputs or center-aligned outputs. For higher period and duty cycle resolution, each pair of adjacent channels ([7:6], [5:4], [3:2], and [1:0]) can be concatenated to form a single 16-bit channel. The module can, therefore, be configured to support 8/0, 6/1, 4/2, 2/3, or 0/4 8-/16-bit channels.

### 1.2.17 Software Watchdog Timer

The watchdog timer is a 32-bit timer that facilitates recovery from runaway code. The watchdog counter is a free-running down-counter that generates a reset on underflow. To prevent a reset, software must periodically restart the countdown.

### 1.2.18 Phase Locked Loop (PLL)

The clock module contains a crystal oscillator, 8 MHz on-chip relaxation oscillator (OCO), phase-locked loop (PLL), reduced frequency divider (RFD), low-power divider status/control registers, and control logic. To improve noise immunity, the PLL, crystal oscillator, and relaxation oscillator have their own power supply inputs: VDDPLL and VSSPLL. All other circuits are powered by the normal supply pins, VDD and VSS.

### 1.2.19 Interrupt Controller (INTC0/INTC1)

There are two interrupt controllers on the MCF52235. These interrupt controllers are organized as seven levels with up to nine interrupt sources per level. Each interrupt source has a unique interrupt vector, and provide each peripheral with all necessary interrupts. Each internal interrupt has a programmable level [1-7] and priority within the level. The seven external interrupts have fixed levels/priorities.

### 1.2.20 DMA Controller

The direct memory access (DMA) controller provides an efficient way to move blocks of data with minimal processor intervention. It has four channels that allow byte, word, longword, or 16-byte burst line transfers. These transfers are triggered by software explicitly setting a DCRn[START] bit or by the occurrence of certain UART or DMA timer events.

### 1.2.21 Reset

The reset controller determines the source of reset, asserts the appropriate reset signals to the system, and keeps track of what caused the last reset. There are seven sources of reset:

- External reset input
- Power-on reset (POR)
- Watchdog timer
- Phase locked-loop (PLL) loss of lock
- PLL loss of clock
- Software



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	1	2	3	4	5	6	7	8	9	10	11
A	TCLK	SDA	SCL	IRQ15	IRQ14	IRQ13	VSSA	VDDA	AN1	AN7	AN5
В	TMS	RCON	GPT0	GPT3	PWM5	PWM1	VRL	VRH	AN2	AN6	AN4
С	TRST	TDO	TDI	GPT2	PWM7	PWM3	IRQ12	ANO	AN3	LNKLED	ACTLED
D	DTIN1	DTIN0	ALLPST	GPT1	VDDX	VDDX	VDD	VDDR	PST2	PST3	SPDLED
Е	DDATA3	IRQ9	IRQ8	VSS	VSS	VDDX	VSS	VDD	PST0	PST1	PHY_RXN
F	DDATA0	DDATA1	DDATA2	VSS	VSS	VSS	VSS	VSS	PHY_VSSRX	PHY_VDDRX	PHY_RXP
G	DTIN2	IRQ5	IRQ6	JTAG_EN	VDDX	VDDX	VDDX	PHY_VSSA	PHY_VSSTX	PHY_VDDTX	PHY_TXP
Н	DTIN3	URTS0	URTS1	QSPI_DIN	QSPI_CS1	VDDX	TEST	TXLED	RXLED	PHY_VDDA	PHY_TXN
J	SYNCB	UCTS0	UCTS1	QSPI_DOUT	QSPI_CS2	RSTI	XTAL	IRQ1	COLLED	DUPLED	PHY_RBIAS
K	SYNCA	URXD0	URXD1	QSPI_CLK	QSPI_CS3	VDDPLL	VSSPLL	IRQ2	IRQ11	URTS2	URXD2
L	IRQ10	UTXD0	UTXD1	QSPI_CS0	IRQ4	RSTO	EXTAL	IRQ3	IRQ7	UCTS2	UTXD2

Figure 4. 121 MAPBGA Pin Assignments

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N			

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Pin Group	Primary Function	SecondaryF unction	Tertiary Function	Quaternary Function	Drive Strength/ Control <sup>1</sup>	Wired OR Control	Pull-up/ Pull-down <sup>2</sup>	Pin on 121 MAPBGA	Pin on 112 LQFP	Pin on 80 LQFP		
Ethernet	ACTLED	—	—	PLD[0]	PDSR[32]	PWOR[8]	—	C11	84	60		
LEDs	COLLED	—	_	PLD[4]	PDSR[36]	PWOR[12]	—	J9	58	42		
	DUPLED	—	—	PLD[3]	PDSR[35]	PWOR[11]	—	J10	59	43		
	LNKLED	—	—	PLD[1]	PDSR[33]	PWOR[9]	—	C10	83	59		
	SPDLED	—	—	PLD[2]	PDSR[34]	PWOR[10]	—	D11	81	57		
	RXLED	—	—	PLD[5]	PDSR[37]	PWOR[13]	—	H9	52	_		
	TXLED	—	—	PLD[6]	PDSR[38]	PWOR[14]	—	H8	51			
	VDDR	—	—	—	—	—	—	D8	82	58		
Ethernet	PHY_RBIAS	—	_	—	_	_		J11	66	46		
PHY	PHY_RXN	—	_	—	—	_		E11	74	54		
	PHY_RXP	—	_	—	—	_		F11	73	53		
	PHY_TXN	—	_	—	—	_		H11	71	51		
	PHY_TXP	—	_	—	—	_		G11	70	50		
	PHY_VDDA <sup>5</sup>	—	_	—		N/A		H10	68	48		
	PHY_VDDRX <sup>5</sup>	—	_	—		N/A		F10	75	55		
	PHY_VDDTX <sup>5</sup>	—	_	—		N/A		G10	69	49		
	PHY_VSSA	—	_	—		N/A		G8	67	47		
	PHY_VSSRX	—	_	—		N/A		F9	76	56		
	PHY_VSSTX	—	—	—		N/A		G9	72	52		
l <sup>2</sup> C	SCL	CANTX <sup>4</sup>	UTXD2	PAS[0]	PDSR[0]	_	Pull-Up <sup>6</sup>	A3	111	79		
	SDA	CANRX <sup>4</sup>	URXD2	PAS[1]	PDSR[0]	_	Pull-Up <sup>6</sup>	A2	112	80		
Interrupts <sup>3</sup>	IRQ15	—	_	PGP[7]	PSDR[47]	—	Pull-Up <sup>6</sup>	A4	106	—		
	IRQ14	—	_	PGP[6]	PSDR[46]	—	Pull-Up <sup>6</sup>	A5	105	—		
	IRQ13	—	_	PGP[5]	PSDR[45]	—	Pull-Up <sup>6</sup>	A6	98	—		
	IRQ12	—	_	PGP[4]	PSDR[44]	—	Pull-Up <sup>6</sup>	C7	97	_		

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Pin Group	Primary Function	SecondaryF unction	Tertiary Function	Quaternary Function	Drive Strength/ Control <sup>1</sup>	Wired OR Control	Pull-up/ Pull-down <sup>2</sup>	Pin on 121 MAPBGA	Pin on 112 LQFP	Pin on 80 LQFP
UART 1 <sup>3</sup>	UCTS1	SYNCA	URXD2	PUB[3]	PDSR[15]	—	—	J3	24	16
	URTS1	SYNCB	UTXD2	PUB[2]	PDSR[14]	—	—	H3	23	15
	URXD1	—	FEC_TXD[0]	PUB[1]	PDSR[13]	PWOR[2]	—	К3	32	23
	UTXD1	-	FEC_COL	PUB[0]	PDSR[12]	PWOR[3]	—	L3	33	24
UART 2	UCTS2	_	—	PUC[3]	PDSR[27]	—	—	L10	61	_
	URTS2	-	—	PUC[2]	PDSR[26]	—	—	K10	60	—
	URXD2	—	—	PUC[1]	PDSR[25]	—	—	K11	62	—
	UTXD2	_	—	PUC[0]	PDSR[24]	—	—	L11	63	_
FlexCAN	SYNCA	CANTX <sup>4</sup>	FEC_MDIO	PAS[3]	PDSR[39]	—	—	—	28	20
	SYNCB	CANRX <sup>4</sup>	FEC_MDC	PAS[2]	PDSR[39]	—	—	—	27	19
VDD <sup>5,11</sup>	VDD	—	—	—	N/A	N/A	—	D7, E8	65,102	45,74
VDDX	VDDX	_	_	—	N/A	N/A	—	D5, D6, E6, G5, G6, G7, H6	14, 43	10, 31
VSS	VSS	—	_	-	N/A	N/A	—	E4, E5, E7,F4, F5, F6, F7, F8	64,101	44,73
VSSX	VSSX	—	—	—	N/A	N/A	—	—	15, 42	11, 30

#### Table 3. Pin Functions by Primary and Alternate Purpose (continued)

<sup>1</sup> The PDSR and PSSR registers are described in Chapter 14, "General Purpose I/O Module. All programmable signals default to 2mA drive in normal (single-chip) mode.

<sup>2</sup> All signals have a pull-up in GPIO mode.

<sup>3</sup> The use of an external PHY limits ADC, interrupt, and QSPI functionality. It also disables the UART0/1 and timer pins.

<sup>4</sup> The multiplexed CANTX and CANRX signals do not have dedicated pins, but are available as muxed replacements for other signals.

<sup>5</sup> The VDD1, VDD2, VDDPLL, and PHY VDD pins are for decoupling only and should not have power directly applied to them.

<sup>6</sup> For primary and GPIO functions only.

<sup>7</sup> Only when JTAG mode is enabled.

<sup>8</sup> For secondary and GPIO functions only.

<sup>9</sup> RSTI has an internal pull-up resistor; however, the use of an external resistor is strongly recommended.

<sup>10</sup> For GPIO function. Primary Function has pull-up control within the GPT module.
 <sup>11</sup> This list for power and ground does not include those dedicated power/ground pins included elsewhere, e.g. in the Ethernet PHY.



# 1.7 Queued Serial Peripheral Interface (QSPI)

Table 8 describes QSPI signals.

Table 8.	Queued	Serial	Periphera	al Interface	(QSPI)	Signals
		•••••				

Signal Name	Abbreviation	Function	I/O
QSPI Synchronous Serial Output	QSPI_DOUT	Provides the serial data from the QSPI and can be programmed to be driven on the rising or falling edge of QSPI_CLK.	0
QSPI Synchronous Serial Data Input	QSPI_DIN	Provides the serial data to the QSPI and can be programmed to be sampled on the rising or falling edge of QSPI_CLK.	I
QSPI Serial Clock	QSPI_CLK	Provides the serial clock from the QSPI. The polarity and phase of QSPI_CLK are programmable.	0
Synchronous Peripheral Chip Selects	QSPI_CS[3:0]	QSPI peripheral chip selects that can be programmed to be active high or low.	0

### **1.8 Fast Ethernet Controller EPHY Signals**

Table 9 describes the Fast Ethernet Controller (FEC) signals.

Signal Name	Abbreviation	Function	I/O
Twisted Pair Input +	RXP	Differential Ethernet twisted-pair input pin. This pin is high-impedance out of reset.	I
Twisted Pair Input -	RXN	Differential Ethernet twisted-pair input pin. This pin is high-impedance out of reset.	Ι
Twisted Pair Output +	TXN	Differential Ethernet twisted-pair output pin. This pin is high-impedance out of reset.	0
Twisted Pair Output -	TXP	Differential Ethernet twisted-pair output pin. This pin is high-impedance out of reset.	0
Bias Control Resistor	RBIAS	Connect a 12.4 k $\Omega$ (1.0%) external resistor, RBIAS, between the PHY_RBIAS pin and analog ground. Place this resistor as near to the chip pin as possible. Stray capacitance must be kept to less than 10 pF (>50 pF causes instability). No high-speed signals can be permitted in the region of RBIAS.	I
Activity LED	ACT_LED	Indicates when the EPHY is transmitting or receiving	0
Link LED	LINK_LED	Indicates when the EPHY has a valid link	0
Speed LED	SPD_LED	Indicates the speed of the EPHY connection	0
Duplex LED	DUPLED	Indicates the duplex (full or half) of the EPHY connection	0
Collision LED	COLLED	Indicates if the EPHY detects a collision	0
Transmit LED	TXLED	Indicates if the EPHY is transmitting	0
Receive LED	RXLED	Indicates if the EPHY is receiving	0

#### Table 9. Fast Ethernet Controller (FEC) Signals





### 1.12 ADC Signals

Table 13 describes the signals of the Analog-to-Digital Converter.

Table 13. ADC Signals

Signal Name	Abbreviation	Function	I/O
Analog Inputs	AN[7:0]	Inputs to the A-to-D converter.	I
Analog Reference	V <sub>RH</sub>	Reference voltage high and low inputs.	I
	V <sub>RL</sub>		I
Analog Supply	V <sub>DDA</sub>	Isolate the ADC circuitry from power supply noise	
	V <sub>SSA</sub>		

### 1.13 General Purpose Timer Signals

Table 14 describes the General Purpose Timer Signals.

#### Table 14. GPT Signals

Signal Name	Abbreviation	Function	I/O
General Purpose Timer Input/Output	GPT[3:0]	Inputs to or outputs from the general purppose timer module	I/O

### 1.14 Pulse Width Modulator Signals

Table 15 describes the PWM signals.

#### Table 15. PWM Signals

Signal Name	Abbreviation	Function	I/O
PWM Output Channels	PWM[7:0]	Pulse width modulated output for PWM channels	0

### 1.15 Debug Support Signals

These signals are used as the interface to the on-chip JTAG controller and also to interface to the BDM logic.

#### Table 16. Debug Support Signals

Signal Name	Abbreviation	Function				
JTAG Enable	JTAG_EN	Select between debug module and JTAG signals at reset	I			
Test Reset	TRST	This active-low signal is used to initialize the JTAG logic asynchronously.	I			
Test Clock	TCLK	Used to synchronize the JTAG logic.	I			
Test Mode Select         TMS         Used to sequence the JTAG state machine. TMS is sampled on the rising edge of TCLK.		I				
Test Data Input	TDI	Serial input for test instructions and data. TDI is sampled on the rising edge of TCLK.	I			



Signal Name	Abbreviation	Function	I/O	
Test Data Output	TDO	Serial output for test instructions and data. TDO is tri-stateable and is actively driven in the shift-IR and shift-DR controller states. TDO changes on the falling edge of TCLK.	0	
Development Serial Clock	DSCLK	Development Serial Clock. Internally synchronized input. (The logic level on DSCLK is validated if it has the same value on two consecutive rising bus clock edges.) Clocks the serial communication port to the debug module during packet transfers. Maximum frequency is PSTCLK/5. At the synchronized rising edge of DSCLK, the data input on DSI is sampled and DSO changes state.	I	
Breakpoint	BKPT	Breakpoint. Input used to request a manual breakpoint. Assertion of BKPT puts the processor into a halted state after the current instruction completes. Halt status is reflected on processor status signals (PST[3:0]) as the value 0xF. If CSR[BKD] is set (disabling normal BKPT functionality), asserting BKPT generates a debug interrupt exception in the processor.		
Development Serial Input	DSI	Development Serial Input. Internally synchronized input that provides data input for the serial communication port to the debug module after the DSCLK has been seen as high (logic 1).	I	
Development Serial Output	DSO	Development Serial Output. Provides serial output communication for debug module responses. DSO is registered internally. The output is delayed from the validation of DSCLK high.	0	
Debug Data	DDATA[3:0]	Display captured processor data and breakpoint status. The CLKOUT signal can be used by the development system to know when to sample DDATA[3:0].	0	
Processor Status Clock	PSTCLK	Processor Status Clock. Delayed version of the processor clock. Its rising edge appears in the center of valid PST and DDATA output. PSTCLK indicates when the development system should sample PST and DDATA values. If real-time trace is not used, setting CSR[PCD] keeps PSTCLK, PST, and DDATA outputs from toggling without disabling triggers. Non-quiescent operation can be re-enabled by clearing CSR[PCD], although the external development systems must resynchronize with the PST and DDATA outputs. PSTCLK starts clocking only when the first non-zero PST value (0xC, 0xD, or 0xF) occurs during system reset exception processing.	0	
Processor Status Outputs	PST[3:0]	Indicate core status. Debug mode timing is synchronous with the processor clock; status is unrelated to the current bus transfer. The CLKOUT signal can be used by the development system to know when to sample PST[3:0].	0	
All Processor Status Outputs	ALLPST	Logical AND of PST[3:0]	0	

### Table 16. Debug Support Signals (continued)





# 2 Electrical Characteristics

This section contains electrical specification tables and reference timing diagrams for the MCF52235, including detailed information on power considerations, DC/AC electrical characteristics, and AC timing specifications.

### NOTE

The parameters specified in this appendix supersede any values found in the module specifications.



### 2.3 DC Electrical Specifications

Table 22. DC Electrical Specifications <sup>1</sup>

Characteristic	Symbol	Min	Max	Unit
Supply voltage	V <sub>DD</sub>	3.0	3.6	V
Input high voltage	V <sub>IH</sub>	$0.7 \times V_{DD}$	4.0	V
Input low voltage	V <sub>IL</sub>	$V_{SS} - 0.3$	0.35 x V <sub>DD</sub>	V
Input hysteresis	V <sub>HYS</sub>	$0.06 \times V_{DD}$	_	mV
Low-voltage detect trip voltage (V <sub>DD</sub> falling)	V <sub>LVD</sub>	2.15	2.3	V
Low-voltage detect hysteresis (V <sub>DD</sub> rising)	V <sub>LVDHYS</sub>	60	120	mV
Input leakage current $V_{in} = V_{DD}$ or $V_{SS}$ , input-only pins	l <sub>in</sub>	-1.0	1.0	μA
High impedance (off-state) leakage current $V_{in} = V_{DD}$ or $V_{SS}$ , all input/output and output pins	I <sub>OZ</sub>	-1.0	1.0	μA
Output high voltage (all input/output and all output pins) $I_{OH} = -2.0 \text{ mA}$	V <sub>OH</sub>	V <sub>DD</sub> - 0.5		V
Output low voltage (all input/output and all output pins) $I_{OL} = 2.0 \text{ mA}$	V <sub>OL</sub>		0.5	V
Weak internal pull-up device current, tested at V <sub>IL</sub> max. <sup>2</sup>	I <sub>APU</sub>	-10	-130	μA
Input capacitance <sup>3</sup> All input-only pins All input/output (three-state) pins	C <sub>in</sub>		7 7	pF
Load capacitance <sup>4</sup> Low drive strength High drive strength	CL		25 50	pF
DC injection current <sup>3, 5, 6, 7</sup> $V_{NEGCLAMP} = V_{SS} - 0.3 V$ , $V_{POSCLAMP} = V_{DD} + 0.3$ Single pin limit Total MCU limit, Includes sum of all stressed pins	I <sub>IC</sub>	-1.0 -10	1.0 10	mA

<sup>1</sup> Refer to Table 25 for additional PLL specifications.

<sup>2</sup> Refer to Table 3 for pins with internal pull-up devices.

<sup>3</sup> This parameter is characterized before qualification rather than 100% tested.

<sup>4</sup> pF load ratings are based on DC loading and are provided as an indication of driver strength. High speed interfaces require transmission line analysis to determine proper drive strength and termination.

<sup>5</sup> All functional non-supply pins are internally clamped to V<sub>SS</sub> and their respective V<sub>DD</sub>.

<sup>6</sup> Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the larger of the two values.

<sup>7</sup> The power supply must maintain regulation within operating  $V_{DD}$  range during instantaneous and operating maximum current conditions. If positive injection current ( $V_{in} > V_{DD}$ ) is greater than  $I_{DD}$ , the injection current may flow out of  $V_{DD}$  and could result in external power supply going out of regulation. Ensure that the external  $V_{DD}$  load shunts current greater than maximum injection current. This is the greatest risk when the MCU is not consuming power. Examples are: if no system clock is present, or if clock rate is very low which would reduce overall power consumption. Also, the system clock is not present during the power-up sequence until the PLL has attained lock.







### 2.8.3 10BASE-T Jab and Unjab Timing

Table 32 and Figure 11 show the relevant 10BASE-T jab and unjab timing parameters.

Parameter	Symbol	Min	Typ <sup>1</sup>	Max	Units
Maximum transmit time	t1		98	—	ms
Unjab time	t2		525	_	ms

<sup>1</sup> Typical values are at 25°C.



Figure 11. 10BASE-T Jab and Unjab Timing



### 2.8.4 Transceiver Characteristics

Parameter	Symbol	Min	Тур	Мах	Units	Test Conditions
Peak differential output voltage	V <sub>OP</sub>	2.2	2.5	2.8	V	With specified transformer and line replaced by 100 $\Omega(\pm 1\%)$ load
Transmit timing jitter	—	0	2	11	ns	Using line model specified in the IEEE 802.3
Receive dc input impedance	Z <sub>in</sub>	_	10		kΩ	0.0 < V <sub>in</sub> < 3.3 V
Receive differential squelch level	V <sub>squelch</sub>	300	400	585	mV	3.3 MHz sine wave input

Parameter	Symbol	Min	Тур	Max	Units	Test Conditions
Transmit Peak Differential Output Voltage	V <sub>OP</sub>	0.95	1.00	1.05	V	With specified transformer and line replaced by 100 $\Omega(\pm 1\%)$ load
Transmit Signal Amplitude Symmetry	V <sub>sym</sub>	98	100	102	%	With specified transformer and line replaced by 100 $\Omega$ (±1%) load
Transmit Rise/Fall Time	t <sub>rf</sub>	3	4	5	ns	With specified transformer and line replaced by 100 $\Omega$ (±1%) load
Transmit Rise/Fall Time Symmetry	t <sub>rfs</sub>	-0.5	0	+0.5	ns	See IEEE 802.3 for details
Transmit Overshoot/UnderShoot	V <sub>osh</sub>	—	2.5	5	%	
Transmit Jitter	—	0	.6	1.4	ns	
Receive Common Mode Voltage	V <sub>cm</sub>	—	1.6	—	V	V <sub>DDRX</sub> = 2.5 V
Receiver Maximum Input Voltage	V <sub>max</sub>	_	_	4.7	V	V <sub>DDRX</sub> = 2.5 V. Internal circuits protected by divider in shutdown

#### Table 34. 100BASE-TX Transceiver Characteristics

## 2.9 Analog-to-Digital Converter (ADC) Parameters

Table 35 lists specifications for the analog-to-digital converter.

### Table 35. ADC Parameters<sup>1</sup>

Name	Characteristic	Min	Typical	Max	Unit
V <sub>REFL</sub>	Low reference voltage	V <sub>SS</sub>	—	V <sub>REFH</sub>	V
V <sub>REFH</sub>	High reference voltage	V <sub>REFL</sub>	—	$V_{DDA}$	V
V <sub>DDA</sub>	Analog supply voltage	3.0	3.3	3.6	V
V <sub>ADIN</sub>	Input voltages	V <sub>REFL</sub>	—	V <sub>REFH</sub>	V
RES	Resolution	12	—	12	bits
INL	Integral non-linearity (full input signal range) <sup>2</sup>	_	±2.5	±3	LSB <sup>3</sup>
INL	Integral non-linearity (10% to 90% input signal range) <sup>4</sup>	_	±2.5	±3	LSB
DNL	Differential non-linearity	_	-1 < DNL < +1	<+1	LSB
	Monotonicity		Guaran	teed	



## 2.13 JTAG and Boundary Scan Timing

Table 39. JTAG and Boundary Scan Timing

Num	Characteristics <sup>1</sup>	Symbol	Min	Max	Unit
J1	TCLK frequency of operation	f <sub>JCYC</sub>	DC	1/4	f <sub>sys/2</sub>
J2	TCLK cycle period	t <sub>JCYC</sub>	$4 \times t_{CYC}$	—	ns
J3	TCLK clock pulse width	t <sub>JCW</sub>	26	—	ns
J4	TCLK rise and fall times	t <sub>JCRF</sub>	0	3	ns
J5	Boundary scan input data setup time to TCLK rise	t <sub>BSDST</sub>	4	—	ns
J6	Boundary scan input data hold time after TCLK rise	t <sub>BSDHT</sub>	26	—	ns
J7	TCLK low to boundary scan output data valid	t <sub>BSDV</sub>	0	33	ns
J8	TCLK low to boundary scan output high Z	t <sub>BSDZ</sub>	0	33	ns
J9	TMS, TDI input data setup time to TCLK rise	t <sub>TAPBST</sub>	4	_	ns
J10	TMS, TDI input data hold time after TCLK rise	t <sub>TAPBHT</sub>	10	—	ns
J11	TCLK low to TDO data valid	t <sub>TDODV</sub>	0	26	ns
J12	TCLK low to TDO high Z	t <sub>TDODZ</sub>	0	8	ns
J13	TRST assert time	t <sub>TRSTAT</sub>	100	_	ns
J14	TRST setup time (negation) to TCLK high	t <sub>TRSTST</sub>	10	_	ns

<sup>1</sup> JTAG\_EN is expected to be a static signal. Hence, it is not associated with any timing.



Figure 14. Test Clock Input Timing



### 2.14 Debug AC Timing Specifications

Table 40 lists specifications for the debug AC timing parameters shown in Figure 19.

Nume	Characteristic	60 M	Unite	
Num	Characteristic	Min	Max	Units
D1	PST, DDATA to CLKOUT setup	4	_	ns
D2	CLKOUT to PST, DDATA hold	1.5	_	ns
D3	DSI-to-DSCLK setup	$1 \times t_{CYC}$	_	ns
D4 <sup>1</sup>	DSCLK-to-DSO hold	$4 \times t_{CYC}$	_	ns
D5	DSCLK cycle time	$5  imes t_{CYC}$	_	ns
D6	BKPT input data setup time to CLKOUT Rise	4	_	ns
D7	BKPT input data hold time to CLKOUT Rise	1.5	_	ns
D8	CLKOUT high to BKPT high Z	0.0	10.0	ns

#### Table 40. Debug AC Timing Specification

<sup>1</sup> DSCLK and DSI are synchronized internally. D4 is measured from the synchronized DSCLK input relative to the rising edge of CLKOUT.

Figure 18 shows real-time trace timing for the values in Table 40.



Figure 18. Real-Time Trace AC Timing

Figure 19 shows BDM serial port AC timing for the values in Table 40.







#### **Mechanical Outline Drawings** 3

This section describes the physical properties of the MCF52235 and its derivatives.

#### 80-pin LQFP Package 3.1









- NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: MILLIMETER. 3. DATUM PLANE-H-- IS LOCATED AT BOTTOM OF LEAD AND IS CONCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE BOTTOM OF THE PARTING LINE. 4. DATUMS -L-, ---- AND -N-TO BE DETERMINED AT DATUM PLANE-H--. 5. DIMENSIONS S AND V TO BE DETERMINED AT SEATING PLANE-T-. 6. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION ALLOWABLE PROTRUSION IS 0.250 (0.010) PER SIDE. DIMENSIONS A AND B DO INCLUDE MOLD MISMATCH AND ARE

- 0.250 (0.010) PER SIDE. DIMENSIONS A AND B DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE –H-. 7. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. DAMBAR PROTRUSION SHALL NOT CAUSE THE LEAD WIDTH TO EXCEED 0.460 (0.013). MINIMUM SPACE BETWEEN PROTRUSION AND ADJACENT LEAD OR PROTRUSION AND ADJACENT LEAD OR

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α	14.00 BSC		0.551 BSC	
A1	7.00 BSC		0.276 BSC	
В	14.00 BSC		0.551 BSC	
B1	7.00 BSC		0.276 BSC	
С		1.60		0.063
C1	0.04	0.24	0.002	0.009
C2	1.30	1.50	0.051	0.059
D	0.22	0.38	0.009	0.015
E	0.40	0.75	0.016	0.030
F	0.17	0.33	0.007	0.013
G	0.65 BSC		0.026 BSC	
J	0.09	0.27	0.004	0.011
K	0.50 REF		0.020 REF	
Р	0.325 BSC		0.013 REF	
R1	0.10	0.20	0.004	0.008
S	16.00 BSC		0.630 BSC	
S1	8.00 BSC		0.315 BSC	
U	0.09	0.16	0.004	0.006
V	16.00 BSC		0.630 BSC	
V1	8.00 BSC		0.315 BSC	
W	0.20 REF		0.008 REF	
Z	1.00 REF		0.039 REF	
0	0 °	10°	0 °	10°
01	0 °		0 °	
02	9 °	14°	9°	14°

CASE 917A-02 **ISSUE C** 

DATE 09/21/95







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TITLE: 112LD LQFP	1	DOCUMENT NO	): 98ASS23330W	REV: E
20 X 20 X 1.4		CASE NUMBER: 987-02		25 MAY 2005
0.65 PITCH		STANDARD: JE	DEC MS-026 BFA	



#### **Revision History**

Revision	Description
8 Sep 2009	Updated Table 25 — PLL Electrical Specifications.
8 April 2010	Updated Table 37— EzPort Electrical Specifications
22 Mar 2011	<ul> <li>Updated Table Oscillator and PLL Electrical Specification. In EXTAL input high voltage updated VDD to 3.0</li> </ul>
23-Mar-2011	<ul> <li>Changed EXTAL input high voltage (External reference) Maximum to "3.0V" (Instead of "VDD"). Also, add a note this value has been updated.</li> <li>Updated clock generation feature</li> </ul>

### Table 41. Revision History (continued)



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